

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|--|---|------------------|---------|------------------|
| S1 | 1782 | 716/1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:51 |
| S2 | 1540 | 716/2 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:50 |
| S3 | 1205 | (716/19) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:51 |
| S4 | 1 | (716/1).ccls. and (yield adj enhancement) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:52 |
| S5 | 4 | (716/2).ccls. and (yield adj enhancement) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:54 |
| S6 | 7 | (716/19).ccls. and (yield adj enhancement) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:55 |
| S7 | 33 | ("716"/\$).ccls. and (yield adj enhancement) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:55 |
| S8 | 1544 | (yield adj enhancement) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:56 |
| S9 | 40 | (yield adj enhancement) and (defect same substrate) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 14:56 |
| S10 | 4 | (yield adj enhancement) same (defect same substrate) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 15:03 |

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|-----|----|---|---|----|-----|------------------|
| S11 | 0 | (yield adj enhancement) and (defect same substrate) and (database) and (design adj information) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 15:18 |
| S12 | 0 | (yield adj (maxim\$ or enhancement)) and (defect same substrate) and (database) and (design adj information) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 16:01 |
| S13 | 0 | (yield near (IC or (integrated adj circuit))) and (defect same substrate) and (database) and (design adj information) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 15:23 |
| S14 | 3 | (yield near (IC or (integrated adj circuit))) and (defect) and (database) and (design adj information) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 15:23 |
| S15 | 8 | (yield adj (maxim\$ or enhancement)) and (design adj information) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 17:13 |
| S16 | 0 | (yield adj (maxim\$ or enhancement)) and ((revis\$ or modify\$ or change) adj (design adj information)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/03/23 17:14 |
| S17 | 4 | (yield adj enhancement) adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/04/01 18:33 |
| S18 | 11 | (yield adj enhancement) and (defect same substrate) and (database) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/07/12 13:21 |
| S19 | 2 | ("6542830").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/07/12 13:21 |